MOSFET - Dual, N & P-Channel, POWERTRENCH®

N-Channel: 150 V, 2.4 A, 155 m Ω P-Channel: -150 V, -0.9 A, 1200 m Ω

FDMC8097AC

General Description

These dual N and P-Channel enhancement mode Power MOSFETs are produced using **onsemi**'s advanced POWERTRENCH process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance. Shrinking the area needed for implementation of active clamp topology; enabling best in class power density.

Features

Q1: N-Channel

- Max $R_{DS(on)} = 155 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 2.4 \text{ A}$
- Max $R_{DS(on)}$ = 212 m Ω at V_{GS} = 6 V, I_D = 2 A

Q2: P-Channel

- Max $R_{DS(on)} = 1200 \text{ m}\Omega$ at $V_{GS} = -10 \text{ V}$, $I_D = -0.9 \text{ A}$
- Max $R_{DS(on)} = 1400 \text{ m}\Omega$ at $V_{GS} = -6 \text{ V}$, $I_D = -0.8 \text{ A}$
- Optimised for Active Clamp Forward Converters
- Pb-Free, Halide Free and RoHS Compliant

Applications

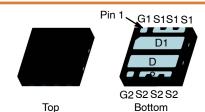
- DC-DC Converter
- Active Clamp

N-Channel

V _{DS} MAX	R _{DS(on)}	I _D MAX
150 V	155 mΩ @ 10 V	2.4 A
	212 mΩ @ 6 V	

P-Channel

V _{DS} MAX	R _{DS(on)}	I _D MAX
–150 V	1200 mΩ @ –10 V	-0.9 A
	1400 mΩ @ –6 V	



WDFN8 3.3 × 3.3, 0.65P (Power 33) CASE 511DG

MARKING DIAGRAM

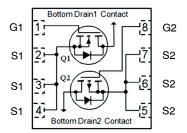
ZXYYKK FDMC 8097AC O

Z = Assembly Plant Code
XYY = 3-Digit Date Code Format
KK = 2-Alphanumeric Lot Run Traceability

Code

FDMC8097AC= Specific Device Code

PIN ASSIGNMENT



ORDERING INFORMATION

Device	Package	Shipping [†]
FDMC8097AC	WDFN8 (Pb-Free, Halide Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

MOSFET MAXIMUM RATINGS ($T_A = 25^{\circ}C$ unless otherwise noted)

Symbol		Q1	Q2	Unit		
V _{DS}	Drain to Source Voltage	Drain to Source Voltage				
V_{GS}	Gate to Source Voltage	Gate to Source Voltage				
I _D	Drain Current	Continuous (Note 5)	T _C = 25°C	6.3	-2.0	Α
		Continuous (Note 5)	T _C = 100°C	3.9	-1.2	
		Continuous	T _A = 25°C	2.4 (Note 1a)	-0.9 (Note 1b)	
		Pulsed (Note 4)	-	33	-8.8	
E _{AS}	Single Pulse Avalanche Energy	(Note 3)		24	6	mJ
P _D	Power Dissipation for Single Op-	peration $T_A = 25^{\circ}C$		1.9 (Note 1a)	1.9 (Note 1b)	W
			T _A = 25°C	0.8 (Note 1c)	0.8 (Note 1d)	
			T _C = 25°C	14	10	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			–55 to	+150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Characteristic	Q1	Q2	Unit
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient	65 (Note 1a)	65 (Note 1b)	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient	155 (Note 1c)	155 (Note 1d)	
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	8.9	12.5	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

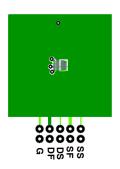
Symbol	Parameter	Test Con	dition	Туре	Min	Тур	Max	Unit
OFF CHAR	ACTERISTICS	•		<u>-</u>		-	<u>-</u>	-
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \; \mu \text{A, V}_{GS} = 0 \; \text{V} \\ I_D = -250 \; \mu \text{A, V}_{GS} = 0 \; \text{V}$		Q1 Q2	150 –150	_ _	- -	V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25°C I_D = -250 μA, referenced to 25°C		Q1 Q2	-	98 122	- -	mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 120 V, V _{GS} = V _{DS} = -120 V, V _{GS} =	0 V = 0 V	Q1 Q2	-	_ _	1 –1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$ $V_{GS} = \pm 25 \text{ V}, V_{DS} = 0$	0 V 0 V	Q1 Q2	1 1	_ _	±100 ±100	nA
ON CHARA	CTERISTICS							
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250$ $V_{GS} = V_{DS}, I_D = -25$		Q1 Q2	2.0 -2.0	3.1 -3.0	4.0 -4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$ /	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, reference I_D = -250 μA, reference		Q1 Q2	-	-9 -6	- -	mV/°C
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 2.4$ $V_{GS} = 6 \text{ V}, I_D = 2 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 2.4$		Q1	- - -	124 155 245	155 212 306	mΩ
		$V_{GS} = -10 \text{ V}, I_D = -0.8 \text{ V}_{GS} = -6 \text{ V}, I_D = -0.8 \text{ V}_{GS} = -10 \text{ V}, I_D = -0.8 \text{ V}_{GS} = -10 \text{ V}$	3 A	Q2	-	930 1030 1682	1200 1400 2171	
9FS	Forward Transconductance	$V_{DD} = 10 \text{ V}, I_D = 2.4 \text{ A}$ $V_{DD} = -10 \text{ V}, I_D = -0.9 \text{ A}$		Q1 Q2	-	6.4 0.75	- -	S
DYNAMIC (CHARACTERISTICS							
C _{iss}	Input Capacitance	Q1 $V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ Q2 $V_{DS} = -75 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		Q1 Q2	- -	279 162	395 230	pF
C _{oss}	Output Capacitance			Q1 Q2		26 13	40 25	pF
C _{rss}	Reverse Transfer Capacitance			Q1 Q2	-	1.4 0.6	5 5	pF
R_g	Gate Resistance			Q1 Q2	0.1 0.1	0.6 3.3	1.5 8.3	Ω
SWITCHING	G CHARACTERISTICS	•				•		•
t _{d(on)}	Turn-On Delay Time	Q1 V _{DD} = 75 V, I _D = 2.4		Q1 Q2	- -	5.4 5.2	11 11	ns
t _r	Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} =$ Q2		Q1 Q2	- -	1.3 1.6	10 10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = -75 \text{ V}, I_{D} = -00 \text{ V}_{GS} = -10 \text{ V}, R_{GEN} = -000 \text{ V}$		Q1 Q2	-	9.1 7.4	18 15	ns
t _f	Fall Time			Q1 Q2	-	2.2 6.3	10 13	ns
Q _{g(TOT)}	Total Gate Charge	V _{GS} = 0 V to 10 V V _{GS} = 0 V to -10 V	Q1 V _{DD} = 75 V, I _D = 2.4 A	Q1 Q2	-	4.4 2.8	6.2 4.0	nC
		V _{GS} = 0 V to 6 V V _{GS} = 0 V to -6 V	Q2 V _{DD} = -75 V I _D = -0.9 A	Q1 Q2	-	2.9 1.8	4.1 2.6	nC
Q _{gs}	Gate to Source Charge	Q1 V _{DD} = 75 V, I _D = 2.4 A		Q1 Q2	-	1.3 0.8	- -	nC
$Q_{\sf gd}$	Gate to Drain "Miller" Charge	Q2 V _{DD} = -75 V I _D = -0.9 A		Q1 Q2	-	1.0 0.7	_ _	nC

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted) (continued)

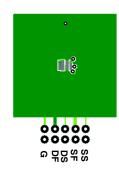
Symbol	Parameter	Test Condition	Туре	Min	Тур	Max	Unit
DRAIN-SOL	DRAIN-SOURCE DIODE CHARACTERISTICS						
V _{SD}	Source-Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_S = 2.4 \text{ A (Note 2)} $ $V_{GS} = 0 \text{ V, } I_S = -0.9 \text{ A (Note 2)} $	Q1 Q2	1 1	0.8 -0.9	1.3 -1.3	V
t _{rr}	Reverse Recovery Time	Q1 I _F = 2.4 A, di/dt = 100 A/s	Q1 Q2	-	50 44	80 71	ns
Q _{rr}	Reverse Recovery Charge	$Q2$ $I_F = -0.9 \text{ A, di/dt} = 100 \text{ A/s}$	Q1 Q2	1 1	43 68	69 109	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. $R_{\theta JA}$ is determined with the device mounted on a 1in2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 65°C/W when mounted a 1 in² pad of 2 oz copp



b) 65°C/W when mounted on a 1 in² pad of 2 oz copper.



c) 155°C/W when mounted on a minimum pad of 2 oz copper.



d) 155°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
 3. Q1: E_{AS} of 24 mJ is based on starting $T_J = 25^{\circ}$ C, L = 3 mH, $I_{AS} = 4$ A, $V_{DD} = 150$ V, $V_{GS} = 10$ V. 100% test at L = 0.1 mH, $I_{AS} = 14$ A. Q2: E_{AS} of 6 mJ is based on starting $T_J = 25^{\circ}$ C, L = 3 mH, $I_{AS} = -2$ A, $V_{DD} = -150$ V, $V_{GS} = -10$ V. 100% test at L = 0.1 mH, $I_{AS} = -8$ A.
 4. Q1: Pulsed Id please refer to Fig 11 SOA graph for more details.
- - Q2: Pulsed Id please refer to Fig 24 SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

TYPICAL CHARACTERISTICS (Q1 N-CHANNEL)

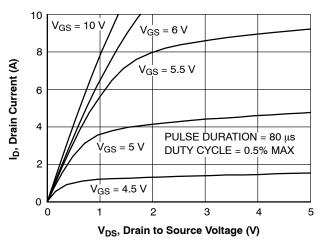


Figure 1. On-Region Characteristics

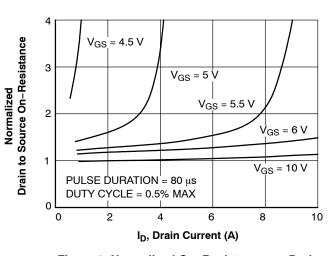


Figure 2. Normalized On–Resistance vs. Drain Current and Gate Voltage

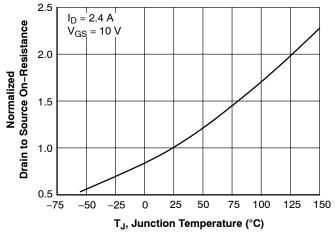


Figure 3. Normalized On–Resistance vs. Junction Temperature

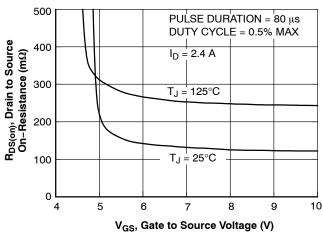


Figure 4. On-Resistance vs. Gate to Source Voltage

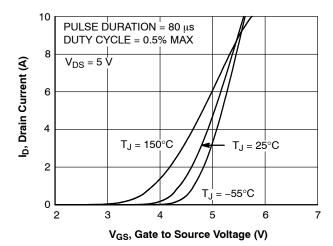


Figure 5. Transfer Characteristics

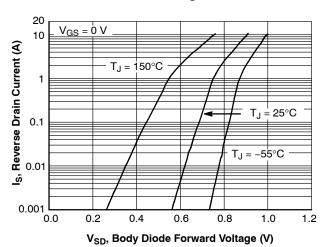


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) (continued)

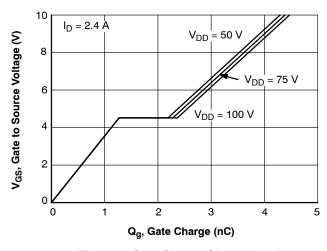


Figure 7. Gate Charge Characteristics

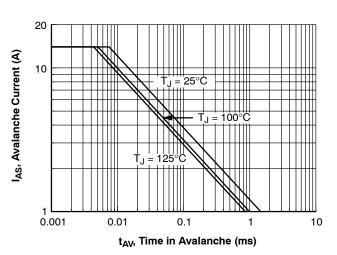


Figure 9. Unclamped Inductive Switching Capability

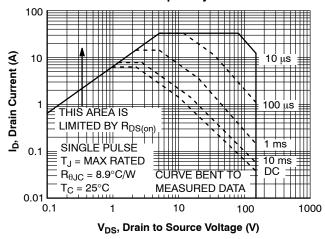


Figure 11. Forward Bias Safe Operating Area

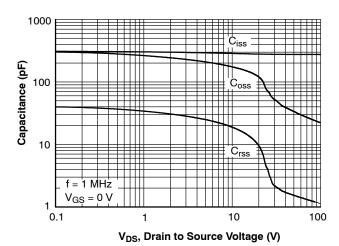


Figure 8. Capacitance vs. Drain to Source Voltage

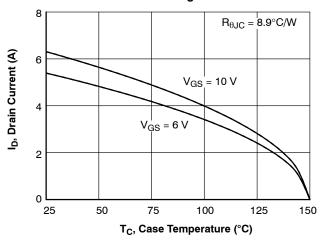


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

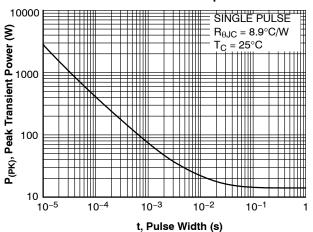


Figure 12. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) (continued)

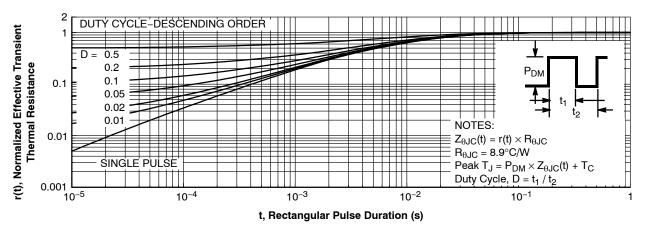


Figure 13. Junction-to-Case Transient Thermal Response Curve

TYPICAL CHARACTERISTICS (Q2 P-CHANNEL)

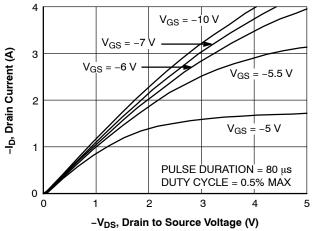


Figure 14. On–Region Characteristics

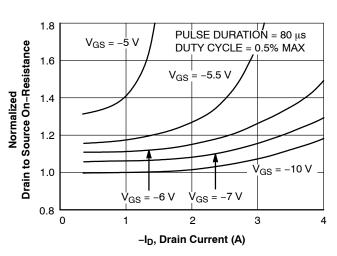


Figure 15. Normalized On-Resistance vs. Drain Current and Gate Voltage

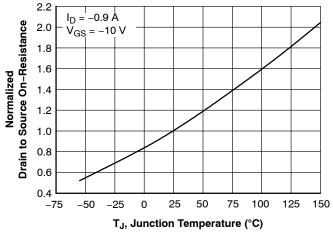


Figure 16. Normalized On–Resistance vs. Junction Temperature

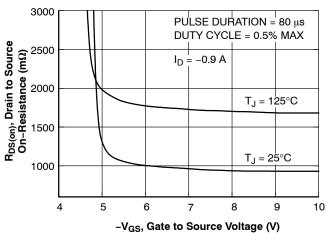


Figure 17. On-Resistance vs. Gate to Source Voltage

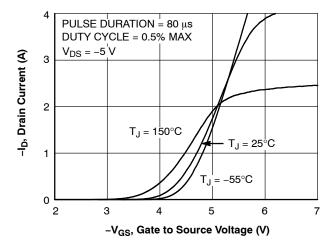


Figure 18. Transfer Characteristics

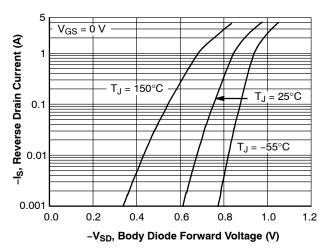


Figure 19. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (Q2 P-CHANNEL) (continued)

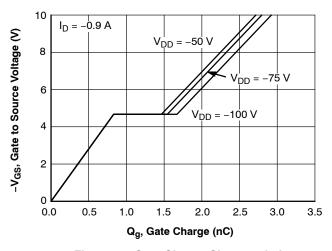


Figure 20. Gate Charge Characteristics

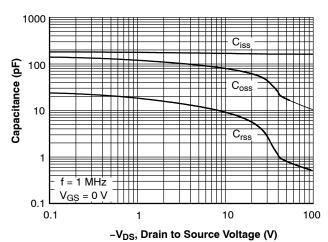


Figure 21. Capacitance vs. Drain to Source Voltage

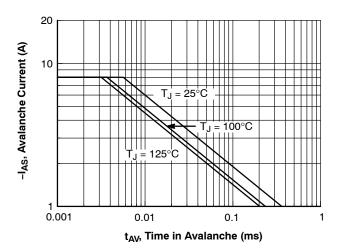


Figure 22. Unclamped Inductive Switching Capability

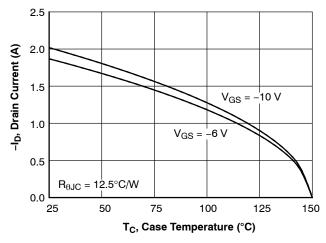


Figure 23. Maximum Continuous Drain Current vs. Case Temperature

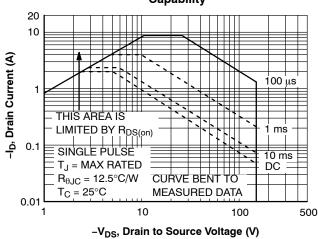


Figure 24. Forward Bias Safe Operating Area

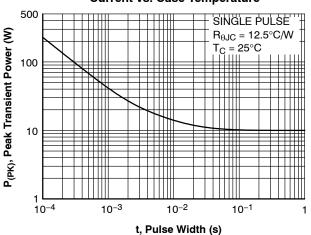


Figure 25. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS (Q2 P-CHANNEL) (continued)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

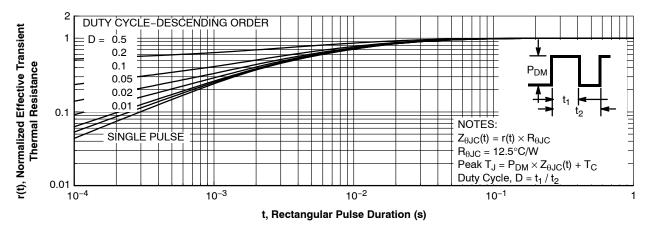
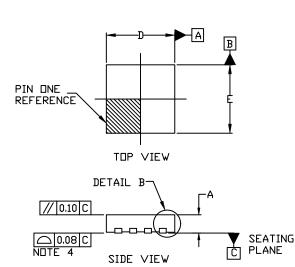


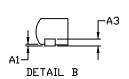
Figure 26. Junction-to-Case Transient Thermal Response Curve

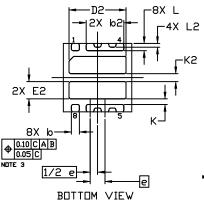
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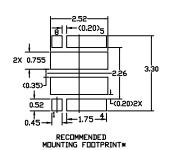
WDFN8 3x3, 0.65P CASE 511DG ISSUE A

DATE 12 FEB 2019









For additional information on our Pb-Free strategy and soldering details, please download the DN Seniconductor Soldering and Mounting Techniques Reference Manual, SDLDERRY/D.

NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. DIMENSION 6 APPLIES TO PLATED TERMINALS AND IS MEASURED BETWEEN 0.15 AND 0.30MM FROM THE TERMINAL TIP.
- COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

	MILLIMETERS			
DIM	MIN.	N□M.	MAX.	
Α	0.70	0.75	0.80	
A1	0.00		0.05	
A3	ĺ	0.20 REF	-	
ھ	0.30	0.35	0.40	
p2	1.65 REF			
D	2.90	3.00	3.10	
D2	2.45	2.50	2.55	
E	2.90	3.00	3.10	
E2	1.40	1.50	1.60	
e		0.65 BSC	;	
К	0.25			
K2	0.35 REF			
L	0.27	0.32	0.37	
L2	0.163 REF			

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON13623G	Electronic versions are uncontrolled except when accessed directly from the Document Repos Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.			
DESCRIPTION:	WDFN8 3x3, 0.65P		PAGE 1 OF 1		

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